

CMT10N10

POWER FIELD EFFECT TRANSISTOR

GENERAL DESCRIPTION

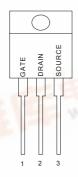
This advanced MOSFET is designed to withstand high energy in avalanche and commutation modes. The new energy efficient design also offers a drain-to-source diode with a fast recovery time. Designed for high voltage, high speed switching applications in power supplies, converters and PWM motor controls, these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating areas are critical and offer additional and safety margin against unexpected voltage transients.

FEATURES

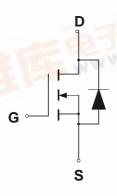
- Avalanche Energy Specified
- Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode
- Diode is Characterized for Use in Bridge Circuits
- I_{DSS} and V_{DS}(on) Specified at Elevated Temperature

PIN CONFIGURATION





SYMBOL



N-Channel MOSFET

ORDERING INFORMATION

Part Number	Package		
CMT10N10N220	TO-220		

ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain to Current — Continuous		10	Α
- Pulsed	I _{DM}	35	
Gate-to-Source Voltage — Continue	V _{GS}	±20	V
 Non-repetitive 	V_{GSM}	±40	V
Total Power Dissipation		40	W
Derate above 25℃		0.32	W/°C
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^{\circ}\mathbb{C}$
Single Pulse Drain-to-Source Avalanche Energy $-T_J = 25^{\circ}$ C		69	mJ
$(V_{DD} = 100V, V_{GS} = 10V, I_{L} = 10A, L = 1.38mH, R_{G} = 25\Omega)$			
Thermal Resistance — Junction to Case	θ_{JC}	3.13	°C/W
 Junction to Ambient 	θ_{JA}	100	
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	T_L	260	$^{\circ}\mathbb{C}$



ELECTRICAL CHARACTERISTICS

Unless otherwise specified, $T_J = 25^{\circ}C$.

			CMT10N10			
Characteristic		Symbol	Min	Тур	Max	Units
Drain-Source Breakdown Voltage		$V_{(BR)DSS}$	100			V
$(V_{GS} = 0 \text{ V}, I_D = 250 \ \mu \text{ A})$						
Drain-Source Leakage Current		I _{DSS}				μA
$(V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V})$					25	
$(V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125^{\circ}\text{C})$					100	
Gate-Source Leakage Current-Forward		I_{GSSF}			100	nA
$(V_{gsf} = 20 \text{ V}, V_{DS} = 0 \text{ V})$						
Gate-Source Leakage Current-Reverse		I_{GSSR}			100	nA
$(V_{gsr} = 20 \text{ V}, V_{DS} = 0 \text{ V})$						
Gate Threshold Voltage		$V_{GS(th)}$	1.0	1.45	2.0	V
$(V_{DS} = V_{GS}, I_D = 250 \ \mu A)$						
Static Drain-Source On-Resistance (V _{GS} =	$5.0 \text{ V}, I_D = 5.0 \text{A}) *$	R _{DS(on)}			0.18	Ω
Drain-Source On-Voltage (V _{GS} = 5.0 V)		$V_{DS(on)}$		1.85	2.6	V
$(I_D = 10 A)$						
Forward Transconductance ($V_{DS} = 50 \text{ V}$, I_{C}) = 5.0A) *	g fs	3.5			mhos
Input Capacitance	$(V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}.$	C_{iss}		741	1040	pF
Output Capacitance	$(v_{DS} - 25 \text{ V}, v_{GS} - 0 \text{ V},$ f = 1.0 MHz)	C_{oss}		175	250	pF
Reverse Transfer Capacitance	1 – 1.0 Wil 12)	C_{rss}		18.9	40	pF
Turn-On Delay Time	$(V_{DD} = 50 \text{ V. } I_D = 10 \text{ A.}$	$t_{d(on)}$		11	20	ns
Rise Time	(55 , 5 ,	t _r		74	150	ns
Turn-Off Delay Time	$V_{GS} = 5.0 \text{ V},$ $R_{G} = 9.1\Omega) *$	$t_{d(off)}$		17	30	ns
Fall Time		t _f		38	80	ns
Total Gate Charge	0/ 00 // 1 40 4	Q_g		9.3	15	nC
Gate-Source Charge	$(V_{DS} = 80 \text{ V}, I_{D} = 10 \text{ A},$	Q_{gs}		2.56		nC
Gate-Drain Charge	V _{GS} = 5.0 V)*	Q_{gd}		4.4		nC
Internal Drain Inductance		L _D		4.5		nH
(Measured from the drain lead 0.25" from	n package to center of die)					
Internal Drain Inductance	_	Ls		7.5		nH
(Measured from the source lead 0.25" from package to source bond pad)						
SOURCE-DRAIN DIODE CHARACTERIS	TICS					
Forward On-Voltage(1)	(1	V _{SD}			1.5	V
Forward Turn-On Time	$(I_S = 10 \text{ A}, V_{GS} = 0 \text{ V},$	t _{on}		**		ns
Reverse Recovery Time	$d_{IS}/d_t = 100A/\mu s)$	t _{rr}		124.7		ns

^{*} Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%

^{**} Negligible, Dominated by circuit inductance



TYPICAL ELECTRICAL CHARACTERISTICS

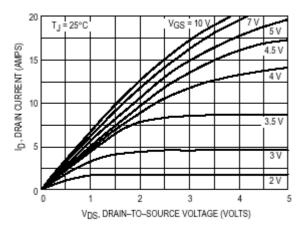


Figure 1. On-Region Characteristics

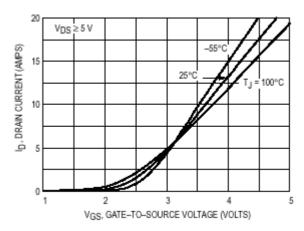


Figure 2. Transfer Characteristics

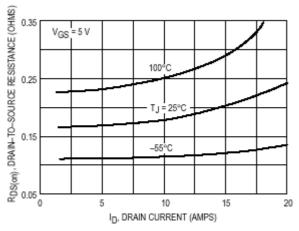


Figure 3. On–Resistance versus Drain Current and Temperature

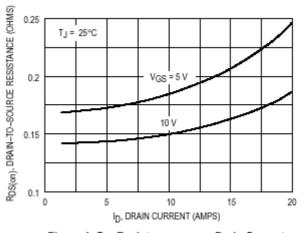


Figure 4. On-Resistance versus Drain Current and Gate Voltage

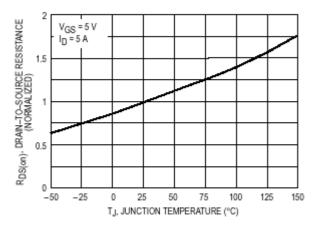


Figure 5. On–Resistance Variation with Temperature

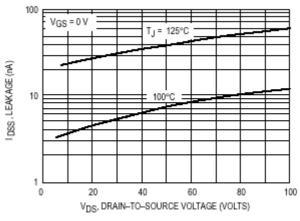
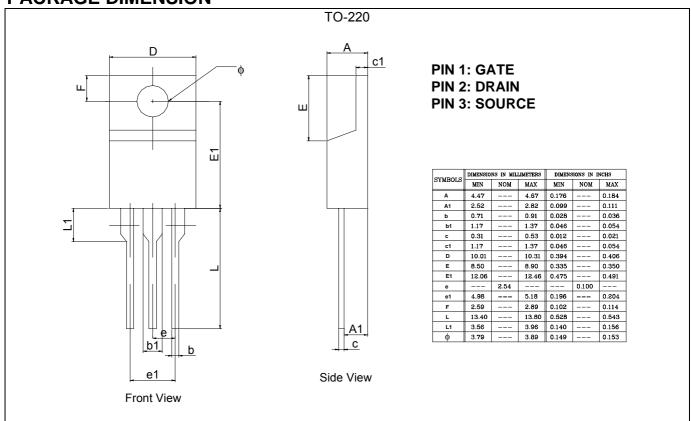


Figure 6. Drain-To-Source Leakage Current versus Voltage



PACKAGE DIMENSION





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